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|-----------------------------------|--|--------------------------|------------------------------------------------------------|-------------|
| <b>Notice of References Cited</b> |  | Application/Control No.  | Applicant(s)/Patent Under Reexamination<br>OSAWA, HIDEHARU |             |
|                                   |  | Examiner<br>Anabel M Ton | Art Unit<br>2875                                           | Page 1 of 1 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|------|----------------|
|   | A | US-6425674                                       | 07-2002         | Su   | 362/31         |
|   | B | US-                                              |                 |      |                |
|   | C | US-                                              |                 |      |                |
|   | D | US-                                              |                 |      |                |
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